

APPLICATION NOTE

MITSUBISHI[®]IGBT MODULE

Preliminary

CM1000DU-34N

| | | | | |
|------|------------|------------|---|---------------------------|
| Pre. | J.Yamada | Rev | D | <i>M. Kaneko</i> |
| Apr. | M.Yamamoto | Dec.14 '01 | | <i>T. Kanno</i> 20-0ct-03 |

HIGH POWER SWITCHING USE

Notice : This is not a final specification. Some parametric limits are subject to change.

捷多邦，专业PCB打样工厂，24小时加急出货

CM1000DU-34NF

- I_{C} 1000A
- V_{CES} 1700V
- Insulated Type
- 2-elements in a pack

APPLICATION

General purpose inverters & Servo controls,etc

ABSOLUTE MAXIMUM RATINGS ($T_j = 25^\circ\text{C}$)

| Symbol | Item | Conditions | Ratings | Units |
|-----------|-------------------------------|---------------------------------------|-----------------|------------------|
| V_{CES} | Collector-emitter voltage | G-E Short | 1700 | V |
| V_{GES} | Gate-emitter voltage | C-E Short | ± 20 | V |
| I_C | Collector current | $T_c = 104^\circ\text{C}$ | 1000 | A |
| I_M | | Pulse | 2000 | |
| I_E ① | Emitter current | $T_c = 25^\circ\text{C}$ | 1000 | A |
| I_M ① | | Pulse | 2000 | A |
| P_C ③ | Maximum collector dissipation | $T_c = 25^\circ\text{C}$ | 3900 | W |
| T_J | Junction temperature | | $-40 \sim +150$ | $^\circ\text{C}$ |
| T_{Stg} | Storage temperature* | | $-40 \sim +125$ | $^\circ\text{C}$ |
| V_{iso} | Isolation voltage | Main terminal to base plate AC 1 min. | 3500 | V |
| — | Torque strength | Main terminal M6 | 3.5 ~ 4.5 | N·m |
| — | Torque strength | Mounting holes M6 | 3.5 ~ 4.5 | N·m |
| — | Weight | Typical value | 1400 | g |

查询CM1000DU-34NF供应商

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ELECTRICAL CHARACTERISTICS ($T_j = 25^\circ\text{C}$)

| Symbol | Item | Conditions | Min. | Typ. | Max. | Units |
|--------------------------------|--|--|------|-------|----------|---------------------------|
| I_{CES} | Collector cutoff current | $V_{CE}=V_{CES}, V_{GE}=0\text{V}$ | — | — | 1 | mA |
| $V_{GE(\text{th})}$ | Gate-emitter threshold voltage | $I_c=100\text{mA}, V_{CE}=10\text{V}$ | 6 | 7 | 8 | V |
| I_{GES} | Gate leakage current | $V_{GE}=V_{GES}, V_{CE}=0\text{V}$ | — | — | 5 | μA |
| $V_{CE(\text{sat})}$ (chip) | Collector to emitter saturation voltage(without lead resistance) | $T_j = 25^\circ\text{C}$ $I_c = 1000\text{A}$ $T_j = 125^\circ\text{C}$ $V_{GE} = 15\text{V}$ ④ | — | 2.2 | 2.8 | V |
| $R(\text{lead})$ | Module lead resistance | $I_c = 1000\text{A}$, terminal-chip | — | 0.286 | — | $\text{m}\Omega$ |
| C_{IES} | Input capacitance | $V_{CE} = 10\text{V}$ | — | — | 220 | nF |
| C_{OES} | Output capacitance | $V_{GE} = 0\text{V}$ | — | — | 25 | nF |
| C_{RES} | Reverse transfer capacitance | — | — | 4.7 | — | — |
| Q_G | Total gate charge | $V_{CC}=1000\text{V}, I_c=1000\text{A}, V_{GE}=15\text{V}$ | — | 6000 | — | nC |
| $t_{d(on)}$ | Turn-on delay time | $V_{CC}=1000\text{V}, I_c=1000\text{A}$ | — | — | 600 | ns |
| t_r | Turn-on rise time | $V_{GE1}=V_{GE2}=15\text{V}$ | — | — | 150 | ns |
| $t_{d(off)}$ | Turn-off delay time | $R_G=0.47\Omega$, Inductive load | — | — | 900 | ns |
| t_f | Turn-off fall time | switching operation | — | — | 200 | ns |
| t_{rr} | Reverse recovery time | $I_E=1000\text{A}$ | — | — | 450 | ns |
| Q_{RR} | Reverse recovery charge | — | — | 90 | — | μC |
| V_{EC} ① | Emitter-collector voltage (without lead resistance) | $I_E=1000\text{A}, V_{GE} = 0\text{V}$ | — | 2.3 | 3 | V |
| $R_{th(j-c)Q}$ | Thermal resistance* | IGBT part (1/2module) FWDi part (1/2module) | — | — | 0.032 | $^\circ\text{C}/\text{W}$ |
| $R_{th(j-c)R}$ | Thermal resistance* | Case to fin, Thermal compound Applied (1/2module) | — | — | 0.053 | $^\circ\text{C}/\text{W}$ |
| $R_{th(c-f)}$ | Contact thermal resistance* | Tc measured point is just under the chips(IGBT part) | — | 0.016 | — | $^\circ\text{C}/\text{W}$ |
| $R_{th(j-c')Q}$ | Thermal resistance* | Tc measured point is just under the chips(FWDi part) | — | — | 0.014 | $^\circ\text{C}/\text{W}$ |
| $R_{th(j-c')R}$ | Thermal resistance* | Tc measured point is just under the chips(FWDi part) | — | — | 0.023 | $^\circ\text{C}/\text{W}$ |
| R_G | External gate resistance | 0.47 | — | 4.7 | Ω | — |

*1: Tc measured point is just under the chips.

If you use this value, $R_{th(f-a)}$ should be measured just under the chips.

*2: Typical value is measured by using Shin-etsu Silicone "G-746".

*3: Tc measured point is shown in page "3-3".

*4: The operation temperature is restrained by the permission temperature of female connector.

① I_E, V_{EC}, t_{rr} & Q_{RR} represent characteristics of the anti-parallel,emitter to collector free-wheel diode (FWDi).

② Pulse width and repetition rate should be such that the device junction temp. (T_j) dose not exceed T_{jmax} rating.

③ Junction temperature (T_j) should not increase beyond 150°C .

④ Pulse width and repetition rate should be such as to cause negligible temperature rise.

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OUTLINE DRAWING

A,B Housing Type

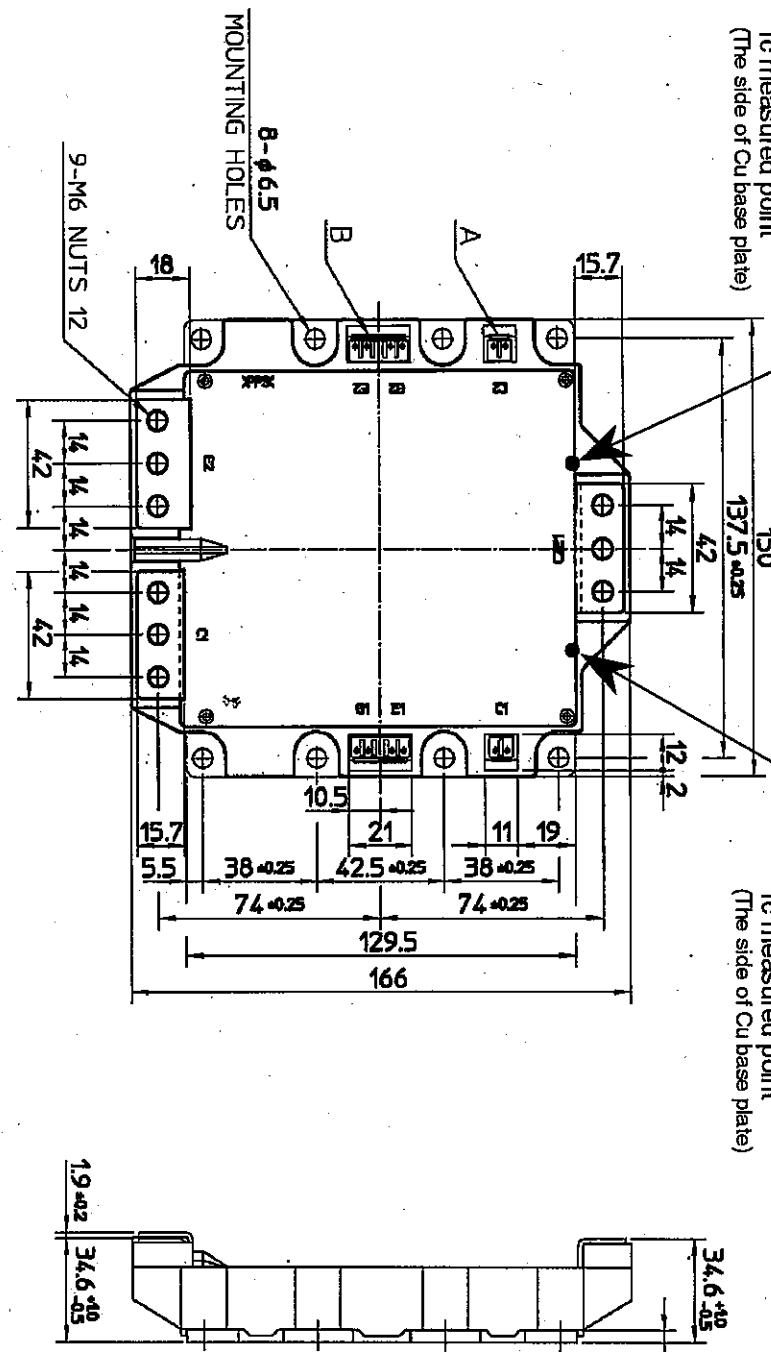
ב.ה.ר.מ.ת.ר.ב.ר.ה.ר.ב.ר.

B : VHR-5N

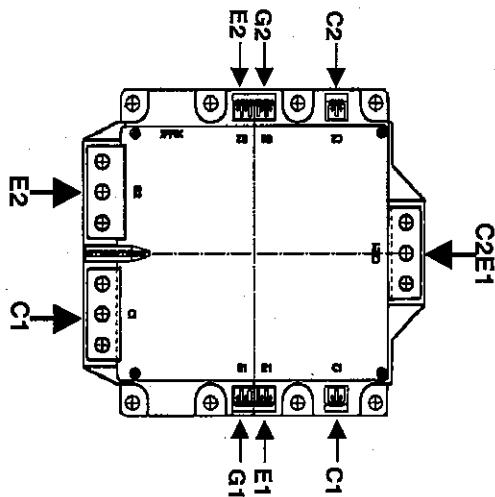
Tc measured p

(The side of Cu base plate)

IC Measured built.
(The side of Cu base plate)



CIRCUIT DIAGRAM



TSM-1626-D

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